## Application/Control No. Applicant(s)/Patent Under Reexamination 10/073,763 HEHLEN ET AL. Notice of References Cited John D. Lee John D. Lie **Examiner** Art Unit Page 1 of 1 2874 U.S. PATENT DOCUMENTS **Document Number** Date \* Name Classification Country Code-Number-Kind Code **MM-YYYY** \* US-6,270,261 08-2001 Kawano, Minoru 385/88 US-В US-US-D US-US-US-G US-US-US-US-US-US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Classification Name Country Code-Number-Kind Code MM-YYYY N 0 P Q S **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.